Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/684,466	CHANG, HYUK
Examiner	**Art Unit**
Julian Mercado	1745

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)	DATE	EXMR
EAST keyword search (attached)	12/1/05	
Inventor search EAST		
above to date	4/13/06	